1 1/2 10S 7/21/03

10/624627
j
1
1
1
<u> </u>

1/3 105 11/13/03

Form PT	PE	*	<u> </u>	U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. MI22-2338					SERIAL NO. 10/624.627		
	3	MBIS	TOF ART CITED	T CITED BY APPLICANT APPLICANT Luan C. Tran							
E MI	y 1.5		Use several sheets			FILING DATE July 21, 2003		GRO 2811	UP		
180	8 TRAD	EMAR		<del></del>	U.S. PATENT DOCUMENTS						
*Examiner Initial			iment ber	Date	Name		Class	Subclass	Filing Date If Appropriate		
94	. <b>AA</b>	6,144	.079 A	11-2000	Shirahata et al.	-			. /		
all	AB	6,033	,952	03-2000	Yasumura, et al.				/-		
Qu	AC	6,124	,168	09-2000	Ong						
<del>Q</del> u	AD	5,688	,705	11-1997	Bergemont						
OU_	AE	5,866	,448	02-1999	Pradeep et al.						
24	AF	5,858	.847	01-1999	Zhou et al.						
ÓU	AG	6,380	1.598	04-2002	Chan						
Qu	AH	6,060	1,364	05-2000	Maszara et al.						
Ш	AI	6,194	,276 B1	02-2001	Chan et al.			/			
()/	AJ.	6,359	,319 B1	03-2002	Noda ·	<u>-</u>					
Qu	AK	5,164	,806	11-1992	Nagatomo et al.						
gu	` AL	4,937	7,756	06-1990	Hsu et al.						
<u> </u>				T	FOREIGN PATENT DOCUMENT	rs	· ·		· · · · · · · · · · · · · · · · · · ·		
		Docu Numi	ement ber	Date	Country		Class	Subclass	Translation Yes No		
94	АМ	EP 0	718881	06/96	EPO, Chan						
	AN		<del> </del>		·						
	AO						·				
	AP-										
			O1	HER REFEREN	CES (including Author, Title, Date,	Pertinent Pages, Etc.)					
	AR	-			<sup>7</sup> Ti-Salicide STI Cell Technology pp. 36.2.1 - 36.2.4.	y for High-Density NO	R Flash Mei	mories and h	ligh Performance		
Ju			,		<del></del>						
$\bigcap I_{I}$	AS		Wolf, S., *Silicon F	Processing for th	e VLSI Era*, Vol. 2, pp. 632-635	).					
14					<del></del>						
Ou	AT		MITSUBISHI ELEC 3/29/2001; *8. Proc	TRIC WEBSITE: fuction Line App	Reprinted from website http://www. lication of a Fine Hole Pattern-F	w.mitsubishlelectric.co ormation Technology	m/r and d/te for Semicond	ch_showcase luctors*, on 3	/ts8.php on . V29/2001, 4 pgs		
4											
EXAMINER	m	R	M.	Ken	DATE CONSIDER	ilo 15	, 20	005			
*EXAMINER: Include copy of	Initial if this form	reren with n	ice considered, whether	or not citation applicant.	is in conformance with MPEP 609			in conformat	oce and not considered.		
						···					

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE SERIAL NO. ATTY, DOCKET NO. HOV 1 3 2003 OF ART CITED BY APPLICANT APPLICANT Luan C. Tran FILING DATE July 21, 2003 GROUP U.S. PATENT DOCUMENTS Document Date Name Subclass Filing Date
If Appropriate Examiner Initial Number 5,930,614 07-1999 Eimori et al. AB 5,635,744 06-1997 Hidaka et al. 6,204,536 03-2001 Macda et al. 6,515,899 B1 02-2003 Tu et al. AD ΑE 4,570,331 02-1986 Eaton, Jr. et al. 6,429,079 B1 08-2002 Maeda et al. AG 6.607.979 B1 08-2003 Kamiyama 4,686,000 08-1987 5,814,875 AJ 09-1998 Kumazaki 5,654,573 08-1997 Oashi et al. ΑK 6,479,330 B2 11-2002 Iwamatsu et al. AL 6,586,803 07-2003 Hidaka et al. FOREIGN PATENT DOCUMENTS Document Date Country Class Subclass Translation Number AN ΑO OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/issues /1998/sep99/docs/feature1.eap on 3/29/2001: "Resists Join the Sub-A Revolution", 9 pgs. AR CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from <a href="http://www.semiconductor.net/semiconductor/issues/1999/aug99/docs/lithography.asp">http://www.semiconductor.net/semiconductor/issues/1999/aug99/docs/lithography.asp</a> on 3/29/2001: "Paths to Smaller Features", 1 pg. ΑT Wolf, S., "Silicon Processing for the VLSI Era, Vol. 1: Process Technology," Lattice Press 1986, pp. 434-437. DA CONSIDERED \*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Included topy of this form with next communication to applicant.

				DEDARTMENT OF COMMERCE	ATTN	·~			
Form PO-14	T E .	6	PATE	DEPARTMENT OF COMMERCE INT AND TRADEMARK OFFICE	ATTY, DOCKET N MI22-2358	<u> </u>		IAL NO. 24,627	
1/	2 MI	(Use several sheets		NT	APPLICANT Luan C. Tran				
A HOA	من در	JCE .			FILING DATE July 21, 2003		GRC 2811		
(B)	ADEMA			U.S. PATENT DOCUMENTS					
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing If Appr	Date opriate
Qu	AA	6,552,401 BI	04-2003	Dennison					
'04	АВ	6,627,524 B2	09-2003	Scott					
Qu	AC	US2002/0182829A1	12-2002	Chen					
94	AD	US2002/0164846A1	11-2002	Lin et al.				Apr. 19, 20	002
94	AE	US2003/0071310A1	04-2003	Salling et al.				Oct. 11, 20	001
-	AF								
	AG		<u> </u>						
	АН								
	Al								
	ĄJ								
	AK								
	AL								
		<del>-</del>		FOREIGN PATENT DOCUMENT	s				
·		Document Number	Date .	Country		Class	Subctass		lation
	AM							Yes	No No
	AN							-	
	AO								
·	AP								
_		01	HER REFEREN	CES (including Author, Title, Date,	Pertinent Pages, Etc.)				
94	AR	IEEE International	Electron Devices	d Manufacturing - DRAM end Em Meeting, Dec. 4, 2001, reprinted m/sessions/s18.html., pp. 1-2.	obedded DRAM Techn 3 11/15/01 from	ology," 2001	IEDM Tech	nicat Program	. 2001
	AS								
	-								
	AT				<del></del>		-		
	<b>/</b>		<del></del> -					<del>-</del>	
EXAMINER	w	if M. &	enn	DATE CONSIDERS	g. 15	. 20	205		
*EXAMINER: Include depy of	Initial if		or not citation i	is in conformance with MPEP 609		tation if not	in conformat	nce and not co	ensidered.
1			•						

1 1DS

MAR-10-2	2004	10:23	WELLS ST	.JOHN, P.S.			50983	383424	P.03/0
Feem FTO:144	,		et P/	A DEPARTMENT OF COMMERCE ATENTAND THAIRMARK OFFICE	ATTY, DOCKETNO.		58 10	BIAL NO.	
		LIST OF ART CITE	D BY APPLICA	NT	APHLICKY ( Less C. Tree		, <u> </u>	-	•
					FILING UNTE July 21, 2003		. CI	KOUP	
<u> </u>				ELMENTINGENER TO			L_		
*Farmings Initial		Document Number	Date	Name		Ch=	Sobriss	Pilin If App	og Dans
Qu	М	6.150.460 B)	est-\$0001	Toad	,				
Qu	A8	6.207,510 Bi	03-2001	Abobs or al.				7	
QU	AC	USZIRO/003011ZAJ	69-\$000	Wadses al.				_	
	ĄĐ							†	
	AE			·					
	AF							<del> </del>	
	. AG							<del>                                     </del>	
	λН							<del> </del>	<del>-</del> .
	N.							<del>                                     </del>	
	A)						<u>-</u>		
	78							+	
	Al.							<del> </del>	
			<u> </u>	FOREXEN PATIENT DING MENTS	<u> </u>			<del></del>	
		Dienamena . Number	Does	Country		Chris	Sieladze	Transparing .	•
	AM				•		<del></del>	Yes	No.
·	AN								
	NO.							1	
	۸Þ		-					·	
	-70		<u> </u>	<del> </del>					
			OTHER REFERE	VCES (Including Author, Title, Dare, Per	isent Pages, Etc.)	•			
	AR		•						
	AS					<del></del>			
	<u> </u>			•	·				
	AT				· · · · · · · · · · · · · · · · · · ·				
	1		<del></del>						
Diaminisa		D 1999 CONSIDERED	Leun	a di	10	اعز	20		
71		Fonce considered, whether or or				<u>/ヴ</u>	20		<u> </u>
_		icados os applicase		ormance with MPEP 6174; Dear line L	ur प्रेम प्रेत त्या है।	conformance	tasii not cuca	rocrot. Include	cupy of
					<u> </u>				1

Form PTO-1449	• .	· .	•	US. DEMAINMENT OF COMMERCE WHEN I AND TRADEMARK OFFICE	MIZZ-ZAR		INE	IAL NO. 24,627	
		LIST OF ART CIT	ED BY APPLIC/ POIS if necessary)	WI.	APPLICANT Lass C. Time				
					FILING DATE (= 1), 2103		GRO 2811		
<del>-</del> .			-	U.S. PATENT DOCUMENTS					
*Farminer Inicid		Document Naturber	Deta	Name		Chen	Subriasa	Filir I r Ap	alandar Pri
QU	~	5,941,185	11-1998	Ishikawa					_
Qu	AB	6,331,458 B1	(2-2001	Anjum et al.	,				
QU	AC:	6,251,744 Bi	05-200)	Su et al.		-			
	AD								
	AΕ								_
	A.F								
	ΛG								
	AH								
	AJ								
	2						·		
	AX								
	Al.								
				FOREIGN PATENT DOCUMENTS		Γ			
		Document Number	Dute	Country		Clus	Subetass	Translution Yes	Π
	AM	-	-						⊨
	AN AD								├
	AΡ								<u> </u>
	ΛQ								
			OTHER REPORT	INCES (including Author, Tule, Date, Po	rrinoss Papra, Ere.)				
	AΩ					· · ·			_
								•	
	AS								
					·	<del> </del>			
	۸ï۲					<del></del> .	<u>-</u>		
				····					
XXXIIXXX	мм	DATECONSIDER	ED Ven	nedy (	Leb	15.	200	)5	
7		V	7000	nformance with MPEP 609; Draw line		,			

JUL-13-1 Ram PTO-1440		14:47	U	T.JOHN, P.S.	ATTY, DOCKET NO.	•	1 533	DAL NO.	P. 00
		LIST OF ART C	H TTED BY APPLICA	A'TEAT AND TRAIDHARK CHYREK INTT	APPLICANT		ADI	24,527	
		(1 pe section	directs if not casely)	R41	Laran C. Tran		<del></del>		
			<del></del>		FILING DATE July 21, 2003		Cild 263	XIP I	
				SELECONEXON EXPLINATION EST			<b></b> -		
*Emvioer hitipal		Distinged Number	fine	Name		Čba	Subeless	Filin LF App	g Date mysiste
94	M	6,521,497	02-2003	Chan at al.					
M	<b>A3</b>	6,41/2,61/4	12-2002	Noble et al.					7
QU	AC	6,469,865 B1	10-2002	Yang et al.					
QU.	۸D	6,451,704 (1)	09-5005	Producty or al.					
	AS:	A,43A,747 (R)	06-2002	Segum et al.			/		
On	AF	4.342.034 B)	07-5005	Sandheri es al.			/	1	
Du	УC	6,277,729 Å1	OH-2001	Deathi es al.			/		
3u	AH	3,923,973	07-1999	Rathrali		/			
21	AI	3,844,934	UZ-1999	Kadosh et ul.					
7	Ą					1			
	AK								
	-81-			·					
			<del></del>	POREIGN PATENT DOCUMENTS		<del></del>	<u></u>	<u> </u>	-
		Cheurpeps Number	l)bra	Спилиту		Class	Subclass	Tembrica	
•								Yes	No
	AM		_			<del></del>			
	AD AD		<del></del>					<del> </del>	<del></del>
	ر <u>ب</u> بر	<u>-</u>				<del></del>			
	40								
			слэнж кюээж	FINCIPS (Including Author, 'Talls, (Juru, Po	rtigen (Pages, 10 s.)			1	
	AR	-							
-	-								
	AS						<del></del>		
	AT			•				<del></del>	
	<u> </u>			· · · · · · · · · · · · · · · · · · ·			•		
XAMINER	<u> </u>	1/ PATE CORNEL	n. Li	enneely	Fel	9 1:	<del>ا</del> ا	200.	<
DOMINER			•	n formance with MPEP 609; I waw line	through classics if cost i		_		
		ication to applicant							••

1.IST OF ART CITED BY APPLICANT   APPLICANT   Loss C. Tills   Filing DATE   CROUT	ate riate									
Part   Part	ate riate									
Passiner   Document   Document   Name   Class   Schelars   Filing   II Approx	ate riase									
Initial   Number   CBM   Scholars   Filing   II Appro	ate riate									
AB 5,369,295 11-1994 VIDAI  AC 5,377,509 03-1995 Mentehi  AD 5,873,728 04-1999 Hisaka  AN 5,672,526 05-1997 Kewaguara  AN 5,272,704 (17-1993 Wakaratya et al.  AA 5,232,704 (17-1993 Wakaratya et al.  AA 1,5,233,102 (10-1994 Yemaguchi et al.  AA 5,856,226 01-1999 Wa  AA 5,877,056 (17-1999 Wa  AA 5,877,056 (17-1999 Wa  AA 6,577,056 (17-1999 Wa  AA 6,277,062 HI 10-2001 Uniter al.  AA 0,297,062 HI 10-2001 Uniter al.  AA US2002,818W692A1 04-2332 Monethy et al.	<u> </u>									
AC   5,397,509   O3-1995   Mendely										
AD   5.873,728   O4-1999   Hisaka	_/									
AK 5,872,526 09-1997 Kewaguan  AV 5,225,704 (17-1993 Wakamiya ei al.  AG 5,441,161 194-1995 Iwamaisu ei al.  AI 5,836,126 114-1999 Wu  AI 5,856,126 114-1999 Wu  AI 5,877,058 (17-1999 Wu  AK 4,518,113 B1 672,71813 Beymuski  AK 6,218,113 B2 11-7003 Maisuch ei al.  AM 6,297,082 H1 10-2001 Lin ei al.  AN US2002ABM3692A1 04-2002 Mondo ei al.	7									
AP 5.225,704 (17-1003) Wakamiya ei al.  AG 5.440,161 (19-1095) Iwamaissi et al.  AI 5.856,126 (11-1099) Wis  AI 5.856,126 (11-1099) Wis  AI 5.857,056 (18-1099) Wis  AK 4.518,113 Bit (52-21913) Boymuski  AL 6.542,531 B2 (11-2003) Matsuch es al.  AM 6.297,082 Hi 10-2001 Un et al.  AN US2002/88/3/592A1 (04-2002) Mascula et al.										
AC 3.44(1,161 104-1995 Iwamatsu et al.  AI 5.856,126 11-1999 Wu  AI 5.856,126 11-1999 Wu  AI 5.877,056 11-1999 Wu  AK 4.518,113 B1 02-21813 Buymuski  AL 6.642,531 B2 11-2003 Matsuch et al.  AM 6,297,082 H1 10-2001 Un et al.  AN US2002/88/3/692A1 04-21872 Macub et al.										
All \$233,112 10-1914 Yemiguchi et al.  Al \$3,856,226 11-1999 Wu  Al \$3,877,056 12X-1999 Wu  Al \$3,877,056 12X-1999 Wu  AK 4,518,113 B1 672-2813 Boymoski  AL 6,642,581 B2 11-2003 Matsuch et al.  AM 6,297,092 H1 10-2001 Life et al.  AN US2002ABM3692A1 04-28X2 Moscula et al.										
AI 5,856,126										
AI 2.977.056 IXL-1999 Wu  AK 4.518.113 B1 G2-21813 Buymuski  AL 6.642.581 B2 11-2U03 Matruth et al.  AM 6.297.082 H1 10-2001 Lin et al.  AN US2002ABM3692A1 04-2XX2 Moscula et al.										
AK 4.518.113 B1 62-21913 Boynoski  AL 6.642.531 B2 11-2003 Matruch et al.  AM 6.297.082 H1 10-2001 Lin et al.  AN US2002ABM3692A1 04-2002 Moscula et al.										
AL 6.542,581 B2 11-2U3 Matsuch et al.  AM 6,297,082 H1 10-2001 Lin et al.  AN US2002ABM3692A1 04-2EX2 Moscula et al.										
AM 6,297,092 HI 10-2001 Lin et al.  AN US2002ABM3692A1 04-2xX2 Mcocda et al.										
AN US2002ABM3692A1 04-2KY? Mordo et al.										
AO USZINIA0189231 10-2003 Clevenger et al.										
FOREIGN PATENT DOCUMENTS										
Programment Date Compley Class Substates Transion										
AP Yes	No.									
10										
OTHER REPERENCES (factualing Author, Title, Date, Pertinent Pages, Etc.)										
AS										
AT										
Deurito M. Dauro de Feb 15 2005										
	EXAMPLES: Initial If reference considered, whether or not citation is in conformance with here 609; Draw line through stration if not in conformance and not considered, actual of other initial conformance and not conformance a									